# **Innovative Silicon & Metal Etch Solution**



## The WaferEtch® Platform

#### **Lowest Cost of Ownership**

- > High throughput
- > On-Board chemical mixing instead of expensive pre-mixed chemistry
- Increased savings with up to 99.5% chemical recapture

#### **Excellent Process Control**

- > Integrated silicon thickness measurement and Profile Match Technology™
- Improved fine-feature etch process control with instant quench
- > Arm movement compensation for radial wafer non-uniformities

#### **Efficient Chemical Management**

- > Multiple chemistries possible in a single chamber
- > No cross-contamination

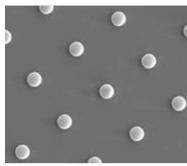


**Precision Surface Processing** 

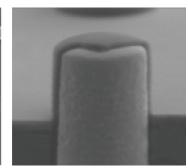
Veeco's single wafer wet etch technology enables uniform selective etching on multiple process levels, free of cross-contamination. Etch uniformity better than 1% is routine. Whether for advanced packaging or BEOL wet etches, WaterEtch systems accomplish the highest yield process at the lowest manufacturing cost. When etch structures or films are needed in the active, backside, and/or bevel areas, WaferEtch systems are a proven technical solution.

### **Unique TSV Reveal Process**

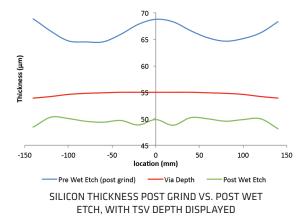
For low-cost TSV reveal processing, the WaferEtch tool is specifically configured to address wafer thinning to reveal the interconnects. This has become a critical step in the manufacture of 2.5D and 3D-IC packaging for process control and cost reduction. WaferEtch replaces four tools required for the dry-etch approach: CMP, plasma etch, silicon thickness measurement and wafer cleaning. Integration of a thickness measurement sensor and Veeco's Profile Match Technology provides closed-loop control of the wafer etching process. WaferEtch achieves a significant reduction in CoO, making 3D TSVs more economically feasible.



TOP VIEW AFTER TSVs REVEALED



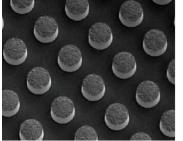
SEM CROSS-SECTION AFTER TSVs REVEALED



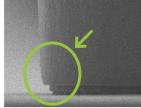
ETCH, WITH TSV DEPTH DISPLAYED

### Additional Etch Processes, Ideal for WaferEtch

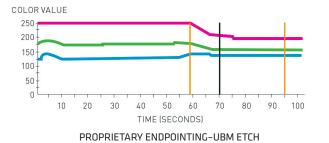
#### **UBM/RDL Etch**



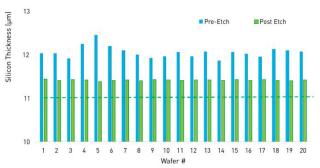
TOP VIEW-AFTER UBM ETCH



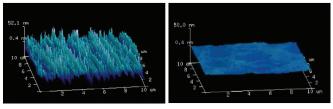
BUMP CROSS-SECTION







HIGHLY REPEATABLE PROCESS



AFM IMAGES BEFORE AND AFTER WAFER THINNING-7X LOWER ROUGHNESS

## Find out more at www.veeco.com or call 1.888.24.VEECO

Veeco Precision Surface Processing 185 Gibraltar Road Horsham, PA 19044 USA +1 215-328-0700



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